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TRADEM Complete if Known Substitute for form 1449B/PTO 09 / 898,521 **Application Number** INFORMATION DISCLOSURE July 3, 2001 Filing Date Charles D. SCHAPER STATEMENT BY APPLICANT First Named Inventor Group Art Unit (use as many sheets as necessary) **Examiner Name** Attorney Docket Number STAN MXL 001 Sheet of

Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T2
87/h		Stephen CHOU, Peter KRAUSS, & Preston RENSTROM. "Imprint Lithography with 25-Nanometer Resolution", Science Vol. 272, April 5, 1996 pp. 85-87, USA.	
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Examiner Date Considered

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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